

Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. <b>455610-2590.2</b>		SERIAL NO. <b>10/673,735</b>	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT <b>Martin MILLER et al.</b>			
FILING DATE <b>September 29, 3003</b>				GROUP <b>2133</b>			

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PC	AA	4,633,465	12/30/86	Fitch et al.	↓	↓	
PC	AB	5,337,403	08/09/94	Klingman			
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
	AQ		
	AR		
	AS		
	AT		
	AU		
	AV		

EXAMINER <b>/Phung Chung/</b>	DATE CONSIDERED <b>07/07/2006</b>
----------------------------------	--------------------------------------

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

00222394

Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO. <b>455610-2590.2</b>		SERIAL NO. <b>10/673,735</b>	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT <b>Martin MILLER et al.</b>			
FILING DATE <b>September 29, 2003</b>				GROUP <b>2133</b>			

OIPE  
 DEC 08 2004  
 U.S. PATENT & TRADEMARK OFFICE

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PC	AA	5,654,987	08/05/97	Nakamura			
	AB	5,726,607	03/10/98	Brede et al			
	AC	5,825,825	10/20/98	Albmann et al			
	AD	5,900,755	05/04/99	Toeppen et al			
	AE	6,215,363	04/10/01	Conta et al			
	AF	6,295,327	09/25/01	Takla			
	AG	6,445,230	09/03/02	Rupp et al			
	AH	4,680,778	07/14/87	Krinoek			
	AJ	5,943,378	08/24/99	Keba et al			
	AJ	6,188,737	02/13/01	Bruce et al			
	AK	5,914,592	06/22/99	Saito			
	AL	5,789,954	08/04/98	Toeppen et al			
PC	AM	4,694,244	08/15/87	Whiteside et al			

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
PC	AN	JP4105070	04/07/92	Japan			Abstract	
	AO	JP5196641	08/06/93	Japan			Abstract	
	AP	JP5264595	10/12/93	Japan			Abstract	
	AQ	JP8220144	06/22/99	Japan			Abstract	
	AR	JP9005362	01/10/97	Japan			Abstract	
	AS	JP10163859	06/19/98	Japan			Abstract	
	AT	JP11098876	04/09/99	Japan			Abstract	
	AU	JP62003544	01/09/87	Japan			Abstract	
	AV	EP 0 631 143	12/28/94	Europe				
PC	AW	EP 0 241 142	10/14/87	Europe				

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)			
PC	AY	Roland E. Best, <i>The Software PLL, Phase Locked Loops</i> , 3 <sup>rd</sup> Edition, McGraw-Hill, New York, 1997, pp 229-249	
	AZ	<i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996	
	BA	HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999	
	BB	Infinium DCA, Agilent Technologies, March 7, 2002	
PC	BC	Communication waveform measurements, Hewlett Packard, June 26, 1996	

EXAMINER <b>/Phung Chung/</b>	DATE CONSIDERED <b>06/27/2006</b>
----------------------------------	--------------------------------------

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Based on Form PTO-1449 (3/90)		ATTY. DOCKET NO. <b>455610-2590.2</b>		SERIAL NO. <b>10/673,735</b>	
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT <b>Martin MILLER et al.</b>			
		FILING DATE <b>September 29, 3003</b>		GROUP <b>2133</b>	

U.S. PATENT DOCUMENTS							
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
BD							
BE							
BF							

FOREIGN PATENT DOCUMENTS							
DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION		
					YES	NO	
BG					Abstract		
BH					Abstract		
BI							

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)		
PC	BJ	Advanced Analysis of High-Speed Digital Communication Waveforms, Hewlett Packard, June 27, 1994
PC	BK	R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999
PC	BL	Technology Standards, Tektronix Website ( <a href="http://www.tek.com/Masurement/Solutions/tech_standards/index.html?wt=257">www.tek.com/Masurement/Solutions/tech_standards/index.html?wt=257</a> )
PC	BM	Communications Signal Analyzer, Tektronix Website ( <a href="http://www.tektronix.com/optical">www.tektronix.com/optical</a> )
PC	BN	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website ( <a href="http://www.Tektronix.com/accessories">www.Tektronix.com/accessories</a> )
PC	BO	Design of FIR Filters by Windowing, MIT Website, ( <a href="http://web.mit.edu/6.555/www/fir.html">http://web.mit.edu/6.555/www/fir.html</a> )
PC	BP	A New Digital PLL at the Technische Universitaet Berlin, Technische Universitaet Berlin Website ( <a href="http://www.tdl.com/gottsch/tuberlin.htm">www.tdl.com/gottsch/tuberlin.htm</a> )
PC	BQ	Low Jitter Digital PLL - ZL30407, Zalink Semiconductor Website, ( <a href="http://products.zalink.com/product_portlets/new_timer.htm">http://products.zalink.com/product_portlets/new_timer.htm</a> )
PC	BR	Michael K. Williams, et al., A Discussion of Methods for Measuring Low-Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-652
PC	BS	Russ Brown, Quantam Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000
PC	BT	Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002
PC	BU	"Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999
PC	BV	Andy Baldman, University of New Hampshire "Description of XAUI Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002
PC	BW	University of New Hampshire Technical Document, "Fast Ethernet" February 13, 2003

EXAMINER <b>/Phung Chung/</b>	DATE CONSIDERED <b>06/27/2006</b>
----------------------------------	--------------------------------------

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

ATTY. DOCKET NO.

455610-2590.2

SERIAL NO.

10/673,735

LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

APPLICANT

Martin MILLER et al.

FILING DATE

September 29, 2003

GROUP

2133

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	AA	5,654,987	08/05/97	Nakamura			
	AB	5,726,607	03/10/98	Brede et al			
	AC	5,825,825	10/20/98	Altmann et al			
	AD	5,900,755	05/04/99	Toeppen et al			
	AE	6,215,363	04/10/01	Conta et al			
	AF	6,295,327	09/25/01	Takla			
	AG	6,445,230	09/03/02	Rupp et al			
	AH	4,680,778	07/14/87	Krinock			
	AJ	5,943,378	08/24/99	Keba et al			
	AK	6,188,737	02/13/01	Bruce et al			
	AL	5,914,592	06/22/99	Saito			
	AM	5,789,954	08/04/98	Toeppen et al			
		4,694,244	08/15/87	Whiteside et al			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AN	JP4105070	04/07/92	Japan			Abstract	
	AO	JP5196641	08/06/93	Japan			Abstract	
	AP	JP5264595	10/12/93	Japan			Abstract	
	AQ	JP8220144	06/22/99	Japan			Abstract	
	AR	JP9005362	01/10/93	Japan			Abstract	
	AS	JP10163859	08/09/98	Japan			Abstract	
	AT	JP11098876	04/09/99	Japan			Abstract	
	AU	JP62003544	01/09/87	Japan			Abstract	
	AV	EP 0 631 143	12/28/94	Europe				
	AW	EP 0 241 142	10/14/87	Europe				

OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

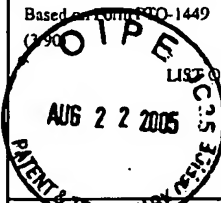
AY		Roland E. Best, <i>The Software PLL, Phase-Locked Loops</i> , 3 <sup>rd</sup> Edition, McGraw-Hill, New York, 1997, pp 229-249
AZ		<i>Using FPGAs for Digital Applications</i> , Actel Corporation, April 1996
BA		HP E4543A Q Factor and Eye Contours Application Software, Hewlett Packard, 1999
BB		Infinium DCA, Agilent Technologies, March 7, 2002
BC		Communication waveform measurements, Hewlett Packard, June 26, 1996

EXAMINER

DATE CONSIDERED

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Based on Form PTO-1449 (1/90)		ATTY. DOCKET NO. <b>455610-2590.2</b>	SERIAL NO. <b>10/673,735</b>			
LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)		APPLICANT <b>Martin MILLER et al.</b>				
		FILING DATE <b>September 29, 2003</b>	GROUP <b>2133</b>			
U.S. PATENT DOCUMENTS						
EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
	BD					
	BE					
	BF					
FOREIGN PATENT DOCUMENTS						
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION
						YES NO
	BG					Abstract
	BH					Abstract
	BI					
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)						
	BJ	Advanced Analysis of High-Speed Digital Communication Waveforms-Hewlett Packard, June 27, 1994				
	BK	R.E. Anderson and E. M. Foster, Design of an MPEG-2 Transport Demultiplexor Core, IBM, 1999				
	BL	Technology Standards, Tektronix Website ( <a href="http://www.tek.com/M Measurement/Solutions/tech_standards/index.html?wr=257">www.tek.com/M Measurement/Solutions/tech_standards/index.html?wr=257</a> )				
	BM	Communications Signal Analyzer, Tektronix Website ( <a href="http://www.tektronix.com/optical">www.tektronix.com/optical</a> )				
	BN	RT-Eye™ Serial Data Compliance and Analysis Software, Tektronix Website ( <a href="http://www.Tektronix.com/accessories">www.Tektronix.com/accessories</a> )				
	BO	Design of FIR Filters by Windowing, MIT Website, ( <a href="http://web.mit.edu/6.555/www/fir.html">http://web.mit.edu/6.555/www/fir.html</a> )				
	BP	A New Digital PLL at the Technische Universität Berlin, Technische Universität Berlin Website ( <a href="http://www.tdl.com/gottsch/tubertin.htm">www.tdl.com/gottsch/tubertin.htm</a> )				
	BQ	Low Jitter Digital PLL - Z130401, Zalink Semiconductor Website, ( <a href="http://products.zalink.com/product_portlets/new_timer.htm">http://products.zalink.com/product_portlets/new_timer.htm</a> )				
	BR	Michael K. Williams, et al., A Discussion of Methods for Measuring Low-Amplitude Jitter, International Test Conference, Paper 28.1, pp 646-652				
	BS	Russ Brown, Quantum Corporation, "Eye Diagram Data", SCSI Physical Working Group, February 9, 2000				
	BT	Dave Fink, Tektronix "Introduction to Measurement Techniques and Analysis of Emerging Serial Data Standards", November 2002				
	BU	"Methodologies for Jitter Specification Technical Report" Rev 10, June 9, 1999				
	BV	Andy Baldman, University of New Hampshire "Description of XAU1 Physical Layer Measurements Performed At The UNH Interoperability Lab", October 30, 2002				
	BW	University of New Hampshire Technical Document, "fast Ethernet" February 13, 2003				
EXAMINER			DATE CONSIDERED			
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.						

Based on Form PTO-1449 (3-90) 	ATTY. DOCKET NO. <b>455610-2590.2</b>	SERIAL NO. <b>10/673,735</b>
	APPLICANT <b>Martin Thomas MILLER et al.</b>	
	FILING DATE <b>September 29, 2003</b>	GROUP <b>2133</b>

## LIST OF REFERENCES CITED BY APPLICANT

(Use several sheets if necessary)

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PC	AA	6,112,160	08/29/00	Salant et al.			
PC	AB	4,876,655	10/24/89	Carlton et al.			
PC	AC	5,180,971	01/19/93	Montijo			
PC	AD	6,522,122	02/18/03	Watanabe et al.			
PC	AE	5,432,791	07/11/95	Gancarcik			
PC	AF	6,539,318	03/25/03	Miller et al.			
PC	AG	6,356,127	03/12/02	Klipper et al.			
PC	AH	4,758,963	07/19/88	Gordon et al.			
PC	AI	4,843,309	06/27/89	Kareem et al.			
PC	AJ	6,571,186	05/27/03	Ward			
PC	AK	2003/0163266	08/28/03	Ward et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
PC	AL	EP 0 444 875	09/04/91	Europe				
PC	AM	EP 1 244 241	09/25/02	Europe				
PC	AN	EP 1 074 845	02/07/01	Europe				
PC	AO	EP 1 118 866	07/25/01	Europe				
PC	AP	WO 00/60806	10/02/00	WIPO				

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

PC	AQ		Dennis Dickerson, "Fiber Optic Test and Measurement (Chapter 8); Prentice Hall PTR, 1998, pps. 284-338
PC	AR		Adam Healey et al., "Fast Ethernet Consortium - 100 Base-TX PMD Test Suite", Version 2.4 and Version 2.5; InterOperability Lab; 1998-1999
PC	AS		Adam Healey, "Fast Ethernet Consortium Notebook", 1996-1997 14 pps.
	AT		
	AU		
	AV		

EXAMINER

/Phung Chung/

DATE CONSIDERED

06/27/2006

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

8/22/05

Sheet 2 of 2

Based on Form PTO-1449 (3/90)  LIST OF REFERENCES CITED BY APPLICANT (Use several sheets if necessary)	ATTY. DOCKET NO. <b>455610-2590.2</b>	SERIAL NO. <b>10/673,735</b>
	APPLICANT <b>Martin Thomas MILLER et al.</b>	
	FILING DATE <b>September 29, 2003</b>	GROUP <b>2133</b>

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PC	AA	6,549,859	04/15/03	Ward			
PC	AB	5,714,878	02/03/98	Saito et al.			
PC	AC	2003/0004664	01/02/03	Ward et al.			
PC	AD	6,009,132	12/28/99	Sholtz			
PC	AE	5,978,742	11/02/99	Pirkerd			
PC	AF	5,761,434	06/02/98	Hewitt			
PC	AG	5,953,071	09/14/99	Van Zon			
PC	AH	6,615,148	09/02/03	Pickerd			
PC	AI	6,642,926	11/04/03	Letts			
PC	AJ	6,044,123	03/28/00	Takla			
PC	AK	5,999,163	12/07/99	Ivers et al.			
PC	AL	5,214,784	05/25/93	Ward et al.			
PC	AM	5,761,537	06/02/98	Sturges et al.			
PC	AN	6,311,138	10/30/01	Miller			
PC	AO	5,402,443	03/28/95	Wong			
PC	AP	6,643,346	11/04/03	Pedrotti et al.			

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AQ							
	AR							

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

AS		
AT		
EXAMINER	/Phung Chung/	
DATE CONSIDERED	06/27/2006	
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.		

00302730

2/28/06

02/28/2006 16:47 FAX 12125880500

FROMMER LAWRENCE &amp; HAUG

004

Sheet 1 of 1

Based on Form PTO-1449 (3/90)  LIST OF REFERENCES CITED BY APPLICANT (Use covers) sheets if necessary	ATTY. DOCKET NO. 455610-2590.2	SERIAL NO. 10/673,735
	APPLICANT Martin Thomas MILLER et al.	
	FILING DATE September 29, 2003	GROUP 2133

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
PC	AA	6,546,345	04/08/03	Ghiasi			
PC	AB	6,278,357	08/21/01	Croushore et al.			
PC	AC	6,366,631	04/02/02	Nakayama et al.			
PC	AD	5,966,684	10/12/99	Richardson et al.			
PC	AE	5,631,759	05/20/97	Bogdan et al.			
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

## FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AL							
	AM							
	AN							
	AO							
	AP							

## OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)

	AQ		
	AR		
	AS		
	AT		
	AU		
	AV		
EXAMINER		DATE CONSIDERED	
/Phung Chung/		06/27/2006	
* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.			

00345727